**Product data sheet** 

### 1. General description

Planar passivated high commutation three quadrant triac in a SOT186A (TO-220F) "full pack" plastic package. This "series ET" triac balances the requirements of commutation performance and gate sensitivity and is intended for interfacing with low power drivers including microcontrollers. It is used in applications where "high junction operating temperature" capability is required.

### 2. Features and benefits

- 3Q technology for improved noise immunity
- · Direct interfacing with low power drivers and microcontrollers
- · Good immunity to false turn-on by dV/dt
- · High commutation capability with sensitive gate
- · High junction operating temperature capability
- High voltage capability
- · Isolated mounting base package
- Planar passivated for voltage ruggedness and reliability
- · Sensitive gate for easy logic level triggering
- · Triggering in three quadrants only

# 3. Applications

- · Applications subject to high temperature
- Industrial and domestic heating circuits
- Motor controls e.g. washing machines and vacuum cleaners
- · Refrigeration and air-conditioner compressor controls

### 4. Quick reference data

#### Table 1. Quick reference data

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|---------------------|--|---|--|-----|-----|-----|------|
| Symbol              | Parameter                                | Conditions  |  | Min | Тур | Max | Unit |
| $V_{DRM}$           | repetitive peak off-state voltage        |   |  | -   | -   | 600 | V    |
| I <sub>T(RMS)</sub> | RMS on-state current                     | full sine wave; T <sub>h</sub> ≤ 98 °C;<br>Fig. 1; Fig. 2; Fig. 3       |  | -   | -   | 10  | Α    |
| I <sub>TSM</sub>    | non-repetitive peak on-<br>state current | full sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 20 ms;<br>Fig. 4; Fig. 5 |  | -   | -   | 100 | Α    |
| T <sub>j</sub>      | junction temperature                     |   |  | -   | -   | 150 | °C   |

| Symbol                | Parameter                             | Conditions   |  | Min | Тур | Max | Unit |
|-----------------------|---------------------------------------|--|--|-----|-----|-----|------|
| Static ch             | Static characteristics                |  |  |     |     |     |      |
| I <sub>GT</sub>       | gate trigger current                  | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$<br>$T_j = 25 ^{\circ}\text{C}; Fig. 7$  |  | 0.5 | -   | 10  | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ \text{ G-};$<br>$T_j = 25 \text{ °C}; Fig. 7$  |  | 0.5 | -   | 10  | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- \text{ G-};$<br>$T_j = 25 \text{ °C}; Fig. 7$  |  | 0.5 | -   | 10  | mA   |
| Dynamic               | characteristics                       |  |  |     |     |     |      |
| $dV_D/d_t$            | rate of rise of off-state voltage     | $V_{DM}$ = 402 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit                                   |  | 50  | -   | -   | V/µs |
| dl <sub>com</sub> /dt | rate of change of commutating current | $V_D = 400 \text{ V}; T_j = 150 ^{\circ}\text{C}; I_{T(RMS)} = 10 \text{ A};$<br>$dV_{com}/dt = 1 \text{ V}/\mu\text{s}; gate open circuit}$ |  | 5   | -   | -   | A/ms |

## 5. Pinning information

### Table 2. Pinning information

| Pin | Symbol | Description             | Simplified outline | Graphic symbol |
|-----|--------|-------------------------|--------------------|----------------|
| 1   | T1     | main terminal 1         | mb                 |                |
| 2   | T2     | main terminal 2         |                    | T2 N T4        |
| 3   | G      | gate                    |                    | sym051         |
| mb  | n.c.   | mounting base; isolated |                    | sym051         |
|     |        |                         |                    |                |

# 6. Ordering information

### Table 3. Ordering information

| Type number   | Package |   |         |  |
|---------------|---------|---|---------|--|
|               | Name    | Description   | Version |  |
| BTA410X-600ET | TO-220F | plastic single-ended package; isolated heatsink mounted; 1 mounting hole; 3-lead TO-220 "full pack" | SOT186A |  |

# 7. Limiting values

#### **Table 4. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol              | Parameter                                | Conditions   |  | Min | Max | Unit             |
|---------------------|--|--|--|-----|-----|------------------|
| $V_{DRM}$           | repetitive peak off-state voltage        |  |  | -   | 600 | V                |
| I <sub>T(RMS)</sub> | RMS on-state current                     | full sine wave; T <sub>h</sub> ≤ 98 °C;<br>Fig. 1; Fig. 2; Fig. 3                    |  | -   | 10  | Α                |
| I <sub>TSM</sub>    | non-repetitive peak on-<br>state current | full sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 20 \text{ ms}$ ; Fig 4; Fig 5 |  | -   | 100 | Α                |
|                     |  | full sine wave; $T_{j(init)} = 25  ^{\circ}C$ ; $t_p = 16.7  \text{ms}$              |  | -   | 110 | А                |
| I <sup>2</sup> t    | I <sup>2</sup> t for fusing              | t <sub>P</sub> = 10 ms; sine-wave pulse  |  | -   | 50  | A <sup>2</sup> s |
| dl <sub>⊤</sub> /dt | rate of rise of on-state current         | I <sub>G</sub> = 20 mA   |  | -   | 100 | A/µs             |
| I <sub>GM</sub>     | peak gate current                        |  |  | -   | 2   | Α                |
| $P_GM$              | peak gate power                          |  |  | -   | 5   | W                |
| $P_{G(AV)}$         | average gate power                       | over any 20 ms period  |  | -   | 0.5 | W                |
| T <sub>stg</sub>    | storage temperature                      |  |  | -40 | 150 | °C               |
| T <sub>j</sub>      | junction temperature                     |  |  | -   | 150 | °C               |

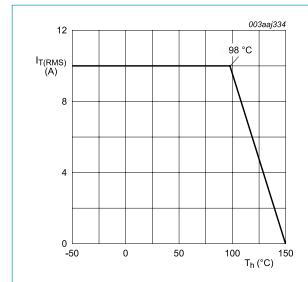


Fig. 1. RMS on-state current as a function of heatsink temperature; maximum values

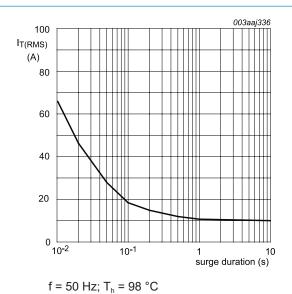
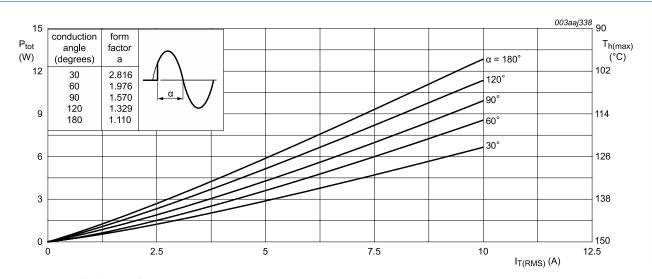


Fig. 2. RMS on-state current as a function of surge duration; maximum values



 $\alpha$  = conduction angle

a = form factor =  $I_{T(RMS)}/I_{T(AV)}$ 

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

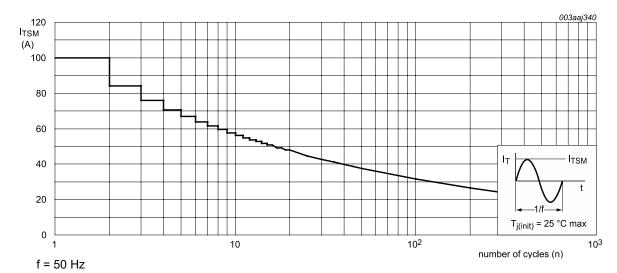


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

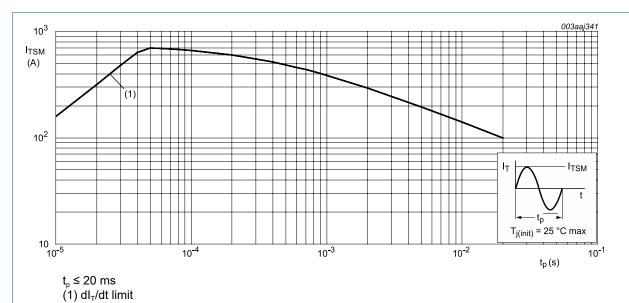
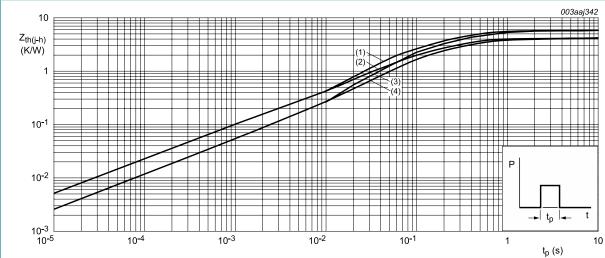


Fig. 5. Non-repetitive peak on-state current as a function of pulse duration; maximum values

### 8. Thermal characteristics

**Table 5. Thermal characteristics** 

| Symbol  | Parameter   | Conditions  | Min | Тур | Max | Unit |
|---|---|---|-----|-----|-----|------|
| R <sub>th(j-h)</sub> thermal resistance from junction to heatsink |   | full cycle or half cycle; with heatsink compound; Fig. 6    | -   | -   | 4   | K/W  |
|   |   | full cycle or half cycle; without heatsink compound; Fig. 6 | -   | -   | 5.5 | K/W  |
| R <sub>th(j-a)</sub>  | thermal resistance<br>from junction to<br>ambient | in free air   | -   | 55  | -   | K/W  |



- (1) Unidirectional (half cycle) without heatsink compound
- (2) Unidirectional (half cycle) with heatsink compound
- (3) Bidirectional (full cycle) without heatsink compound
- (4) Bidirectional (full cycle) with heatsink compound

Fig. 6. Transient thermal impedance from junction to heatsink as a function of pulse duration

### 9. Isolation characteristics

**Table 6. Isolation characteristics** 

| Symbol                 | Parameter             | Conditions  | Min | Тур | Max  | Unit |
|------------------------|-----------------------|---|-----|-----|------|------|
| V <sub>isol(RMS)</sub> | RMS isolation voltage | from all terminals to external heatsink; sinusoidal waveform; clean and dust free; 50 Hz $\leq$ f $\leq$ 60 Hz; RH $\leq$ 65 %; $T_h = 25$ °C | -   | -   | 2500 | V    |
| C <sub>isol</sub>      | isolation capacitance | from main terminal 2 to external heatsink; f = 1 MHz; T <sub>h</sub> = 25 °C  | -   | 10  | -    | pF   |

## 10. Characteristics

### **Table 7. Characteristics**

| Symbol                | Parameter                             | Conditions  | Min  | Тур | Max | Unit |
|-----------------------|---------------------------------------|---|------|-----|-----|------|
| Static ch             | aracteristics                         |   |      |     | '   |      |
| I <sub>GT</sub>       | gate trigger current                  | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$<br>$T_j = 25 \text{ °C}; Fig. 7$   | 0.5  | -   | 10  | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ \text{ G-};$<br>$T_j = 25 \text{ °C}; Fig. 7$   | 0.5  | -   | 10  | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- \text{G-};$<br>$T_j = 25 \text{ °C}; \underline{\text{Fig. 7}}$   | 0.5  | -   | 10  | mA   |
| I <sub>L</sub>        | latching current                      | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G+;  T_j = 25 °C; Fig. 8$   | -    | -   | 25  | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ \text{ G-};$<br>$T_j = 25 \text{ °C}; Fig. 8$   | -    | -   | 30  | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G-};$<br>$T_j = 25 \text{ °C}; \underline{\text{Fig. 8}}$  | -    | -   | 25  | mA   |
| I <sub>H</sub>        | holding current                       | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>  | -    | -   | 15  | mA   |
| $V_T$                 | on-state voltage                      | I <sub>T</sub> = 15 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>   | -    | 1.3 | 1.6 | V    |
| $V_{GT}$              | gate trigger voltage                  | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>   | -    | 0.7 | 1   | V    |
|                       |                                       | V <sub>D</sub> = 400 V; T <sub>j</sub> = 150 °C; <u>Fig. 11</u>   | 0.25 | 0.4 | -   | V    |
| I <sub>D</sub>        | off-state current                     | V <sub>D</sub> = 600 V; T <sub>j</sub> = 150 °C   | -    | 0.4 | 2   | mA   |
| Dynamic               | characteristics                       |   |      |     | '   |      |
| dV <sub>D</sub> /dt   | rate of rise of off-state voltage     | $V_{DM}$ = 402 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit  | 50   | -   | -   | V/µs |
| dI <sub>com</sub> /dt | rate of change of commutating current | $V_D = 400 \text{ V; } T_j = 150 \text{ °C; } I_{T(RMS)} = 10 \text{ A;}$<br>$dV_{com}/dt = 20 \text{ V/}\mu\text{s; (snubberless condition); gate open circuit}$ | 2    | -   | -   | A/ms |
|                       |                                       | $V_D = 400 \text{ V}; T_j = 150 ^{\circ}\text{C}; I_{T(RMS)} = 10 \text{ A};$<br>$dV_{com}/dt = 10 \text{ V}/\mu\text{s}; gate open circuit}$                     | 3.5  | -   | -   | A/ms |
|                       |                                       | $V_D = 400 \text{ V}; T_j = 150 \text{ °C}; I_{T(RMS)} = 10 \text{ A};$<br>$dV_{com}/dt = 1 \text{ V/}\mu\text{s}; gate open circuit}$                            | 5    | -   | -   | A/ms |

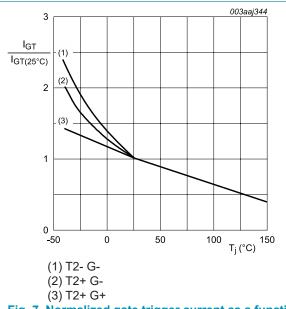


Fig. 7. Normalized gate trigger current as a function of junction temperature

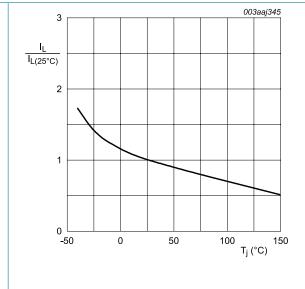


Fig. 8. Normalized latching current as a function of junction temperature

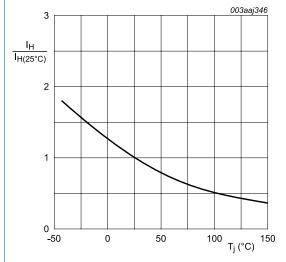
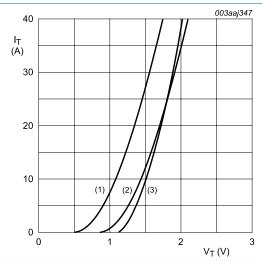


Fig. 9. Normalized holding current as a function of junction temperature



 $V_o$  = 1.142 V;  $R_s$  = 0.027  $\Omega$ 

(1) T<sub>j</sub> = 150 °C; typical values (2) T<sub>j</sub> = 150 °C; maximum values

(3) T<sub>i</sub> = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

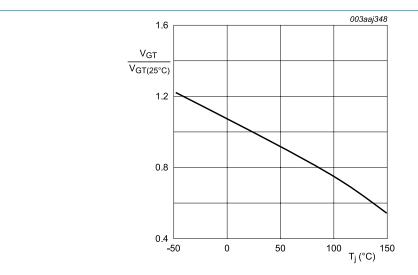
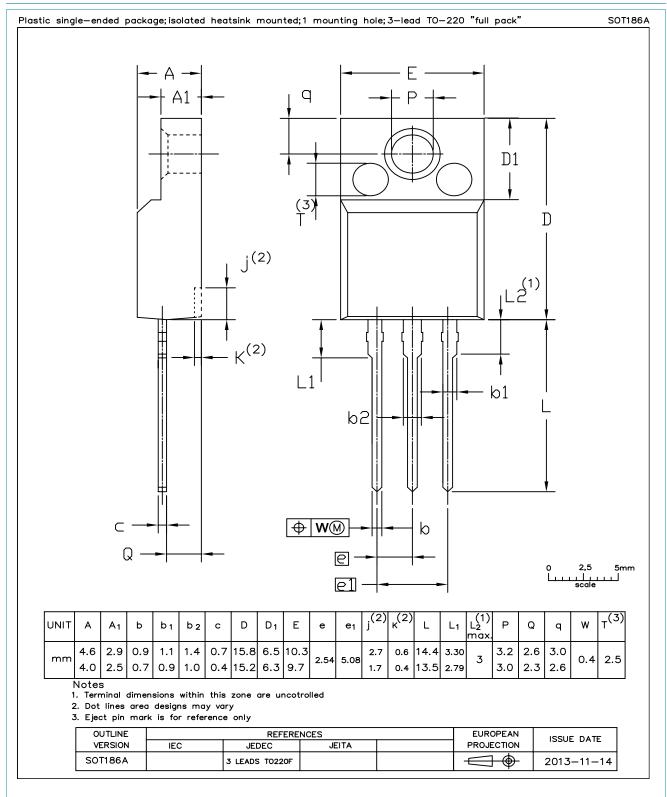


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

# 11. Package outline



### 12. Legal information

#### Data sheet status

| Document status [1][2]               | Product status [3] | Definition  |
|--------------------------------------|--------------------|---|
| Objective<br>[short] data<br>sheet   | Development        | This document contains data from the objective specification for product development. |
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